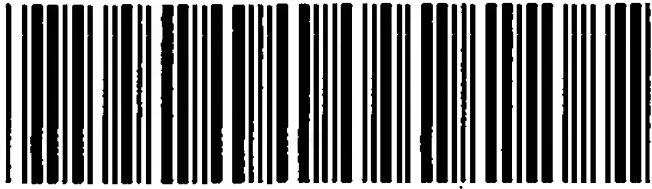


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/662,003	LEE ET AL.	
	Examiner	Art Unit	
	Young J. Kim	1637	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference Search History - see print out		11/7/2007	YJK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	11/7/2007	YJK
SEQ ID NO: 3, 4, and 12	11/7/2007	YJK